Sc688 U.S. PTO 09/624014 07/21/00

Class	Subclass	ISSUE CLASSIFICATION

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E. SCANNED ____ Q.A. ____	PATENT DATE

LICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/624014	F	702	117	2857	

APPLICANTS: Hideaki Sakaguchi

TITLE: Testing device and testing method for semiconductor integrated circuits

PTO-2040 12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)

INTERNATIONAL CLASSIFICATION

☐ Continued on Issue Slip Inside File Jacket

BEST AVAILABLE COPY

☐ TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
☐ The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____	(Assistant Examiner) _____ (Date)				
☐ The terminal ____months of this patent have been disclaimed.	(Primary Examiner) _____ (Date)			ISSUE FEE: Amount Due / Date Paid	
	(Legal Instruments Examiner) _____ (Date)			ISSUE BATCH NUMBER	

WARNING:
The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-436A (Rev. 6/99)

FILED WITH: ☐ DISK (CRF) ☐ FICHE ☐ CD-ROM
(Attached in pocket on right inside flap)